



# Midas at Mu3e: Pixel QC test

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Midas Workshop  
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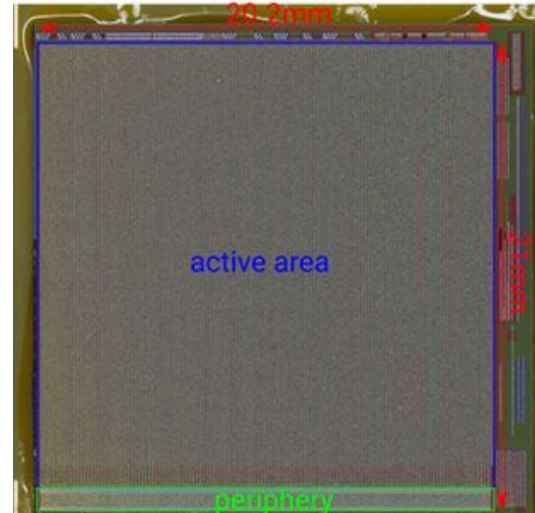
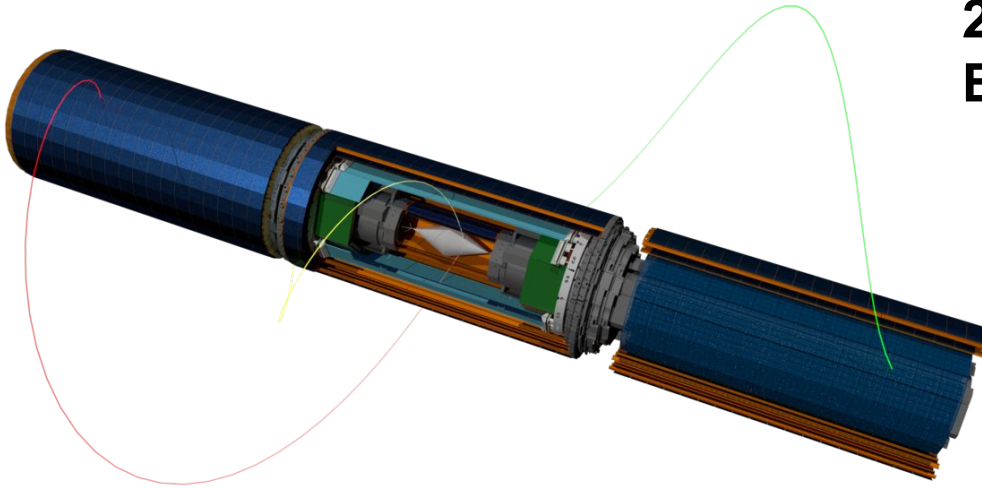
# Mu3e at PSI

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Mu3e aims to observe/exclude the  $\mu \rightarrow eee$  decay with  $10^{16}$  single event sensitivity

**Tracking system needed!**  
**2844 HV-MAPS: Mupix11**  
**Each 20x21x0.05 mm<sup>3</sup>**



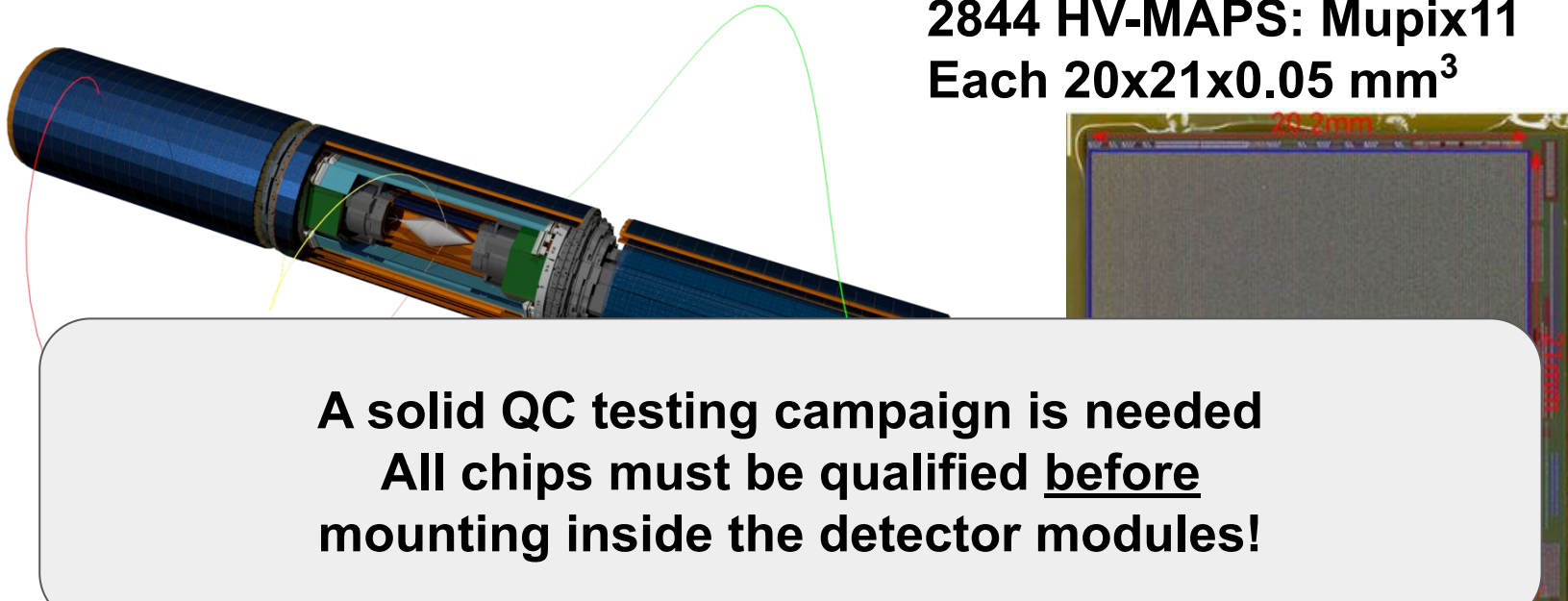
# Mu3e at PSI

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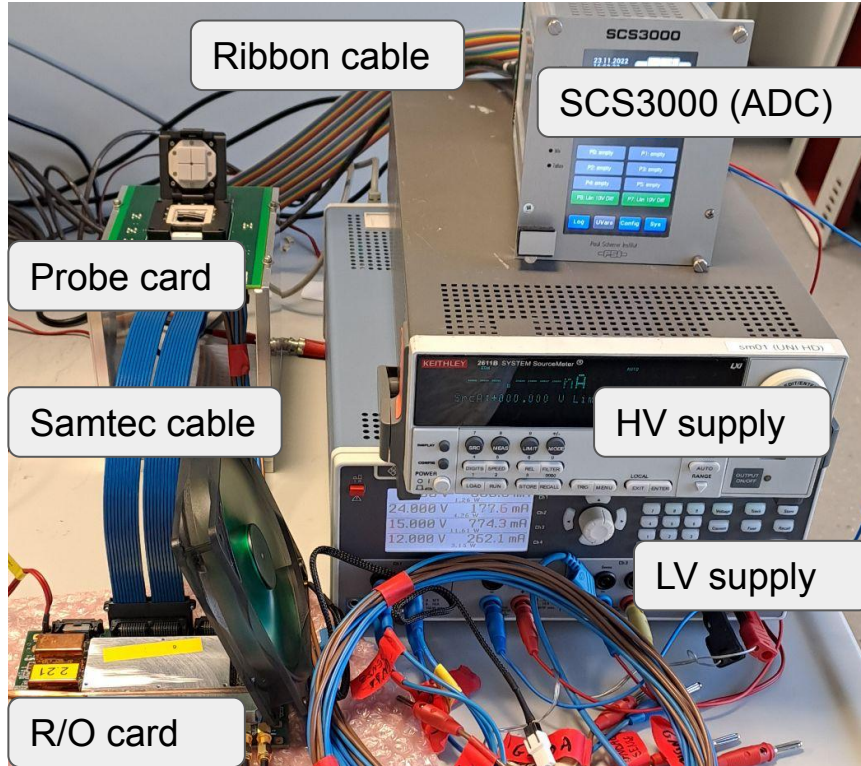
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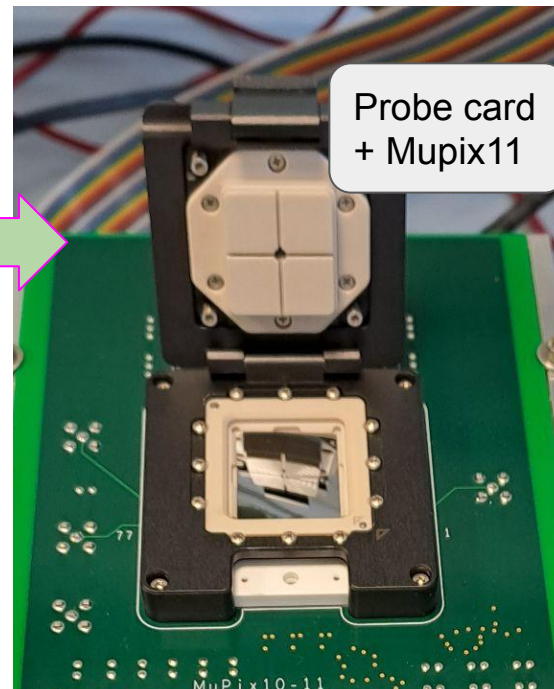
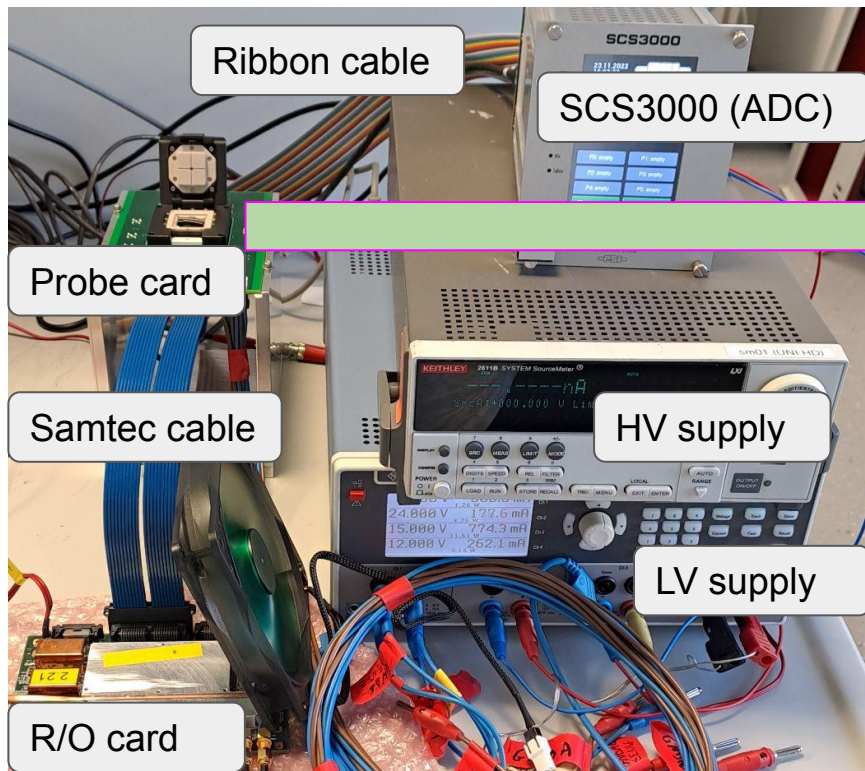


**A solid QC testing campaign is needed**  
**All chips must be qualified before**  
**mounting inside the detector modules!**

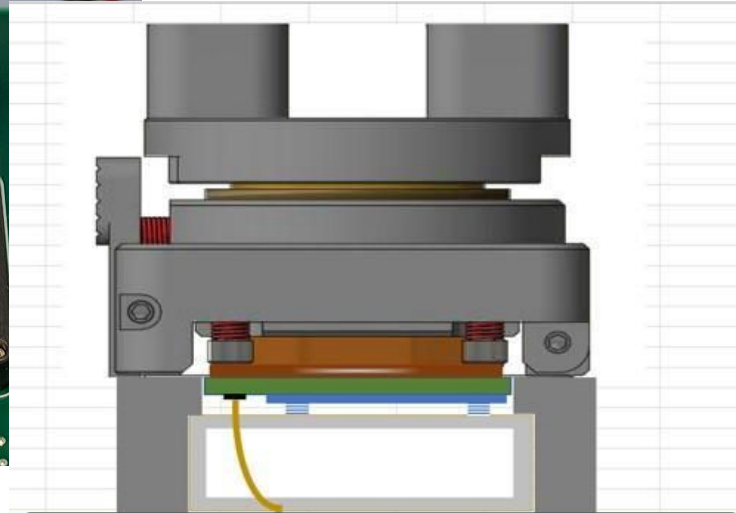
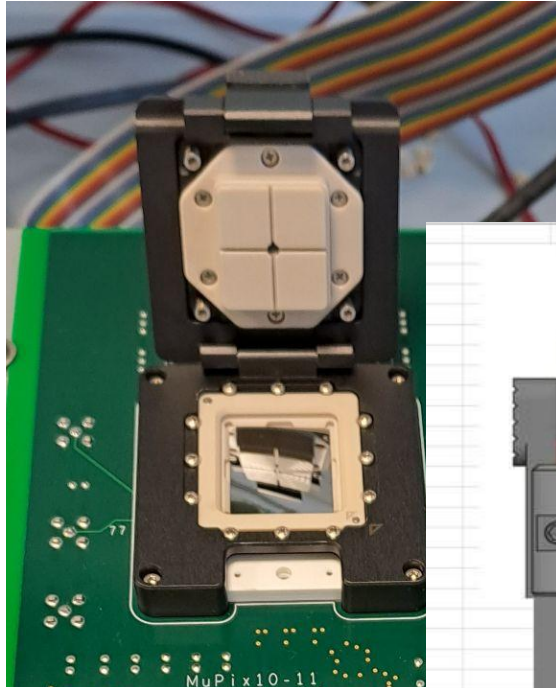
# QC test setup: hardware



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# QC test setup: hardware



Probe card + Mupix11  
Section view

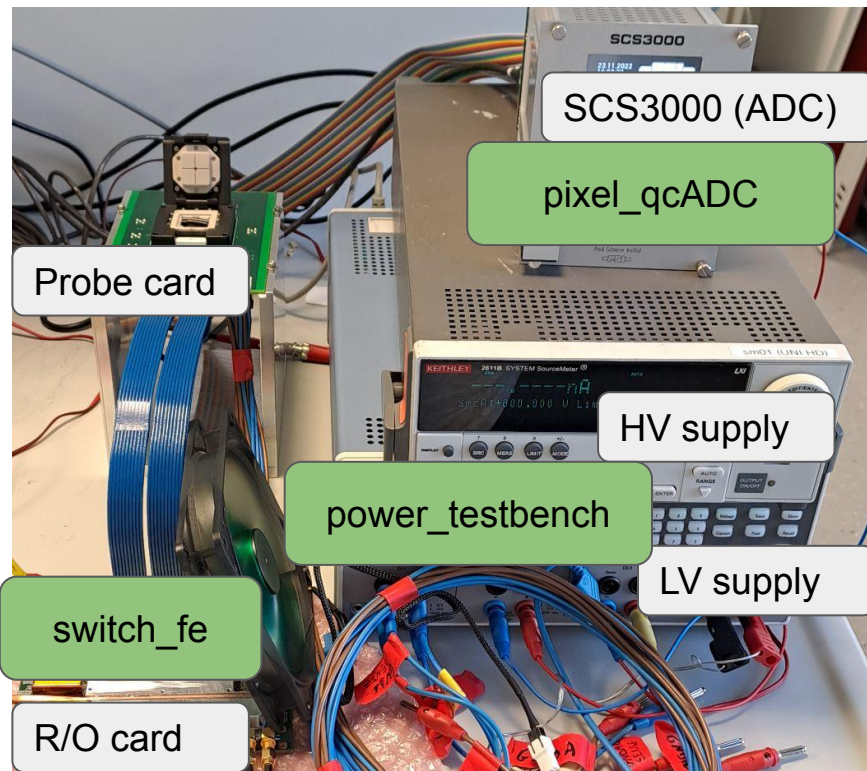
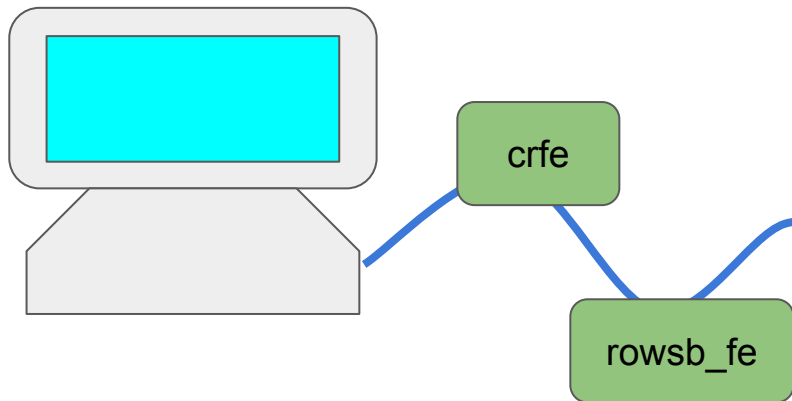
- Chip inserted in guides
- Needles sticking out of PCB against the chip
- Manual actuator presses chip onto needles
- Electrical contact in place
- Tests can be carried out
- Mu3e miniDAQ used: compact version of the DAQ shown in the previous presentation

# QC test setup: software



Based on MIDAS

Several **front-ends** for the different components



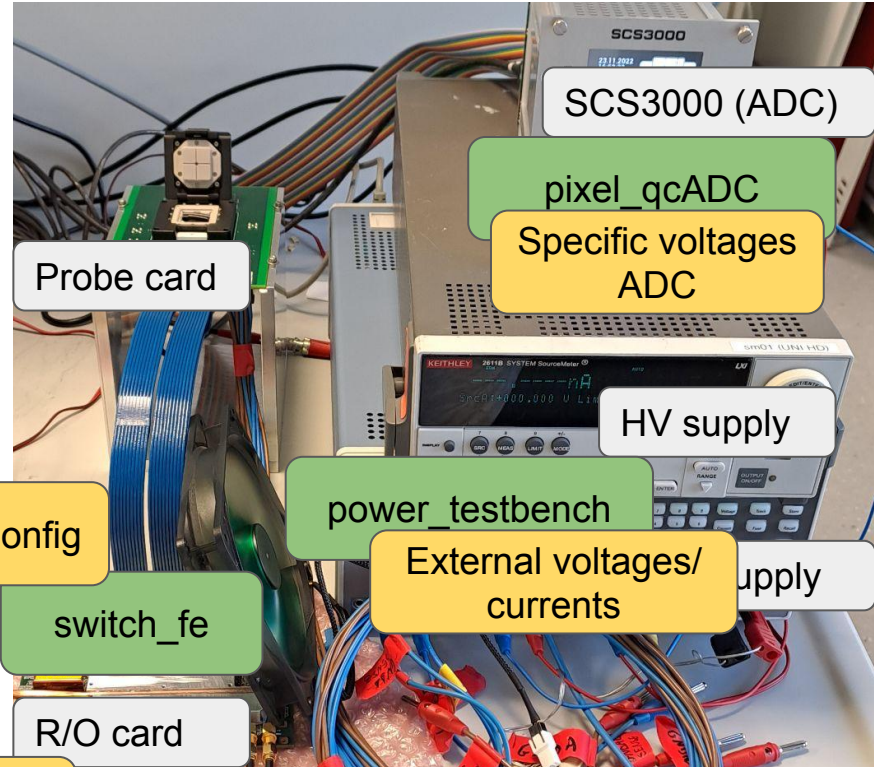
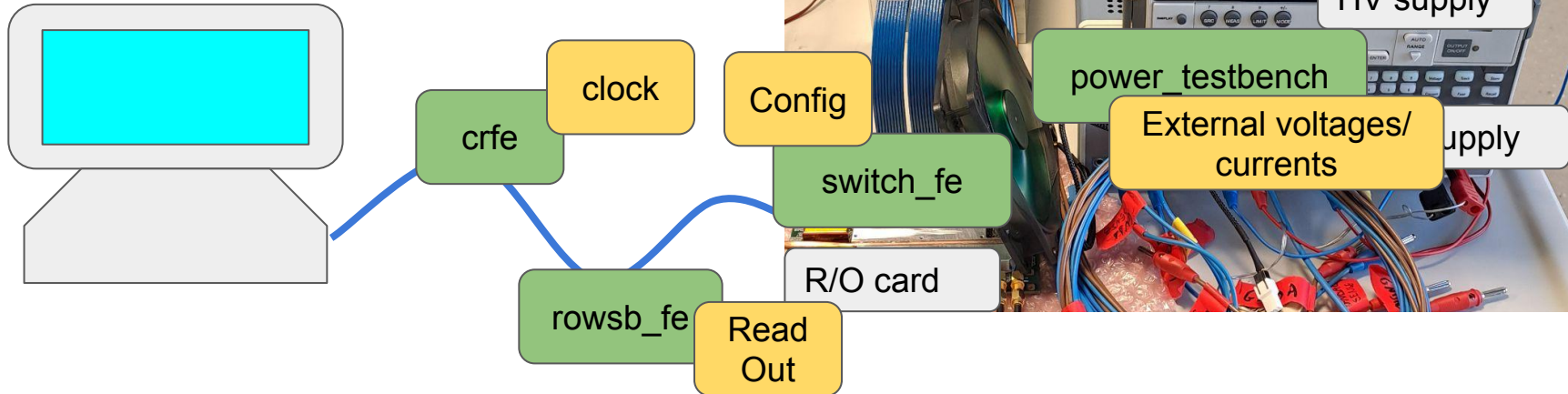
# QC test setup: software



Based on MIDAS

Several **front-ends** for the different components

Each with its **functionality**







# QC test setup: software principle

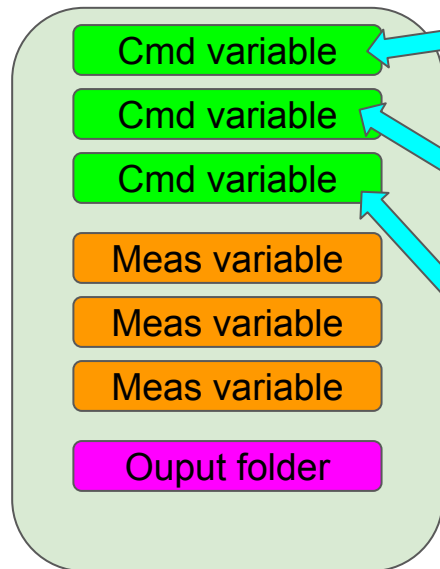
One full QC test is a sequence of single tests

Each single test is run by a sequencer script

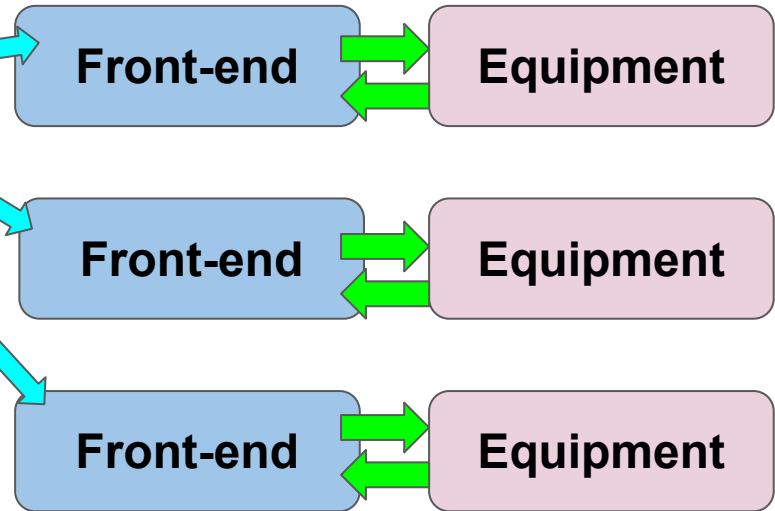
## Sequencer script



## ODB



odb\_watch

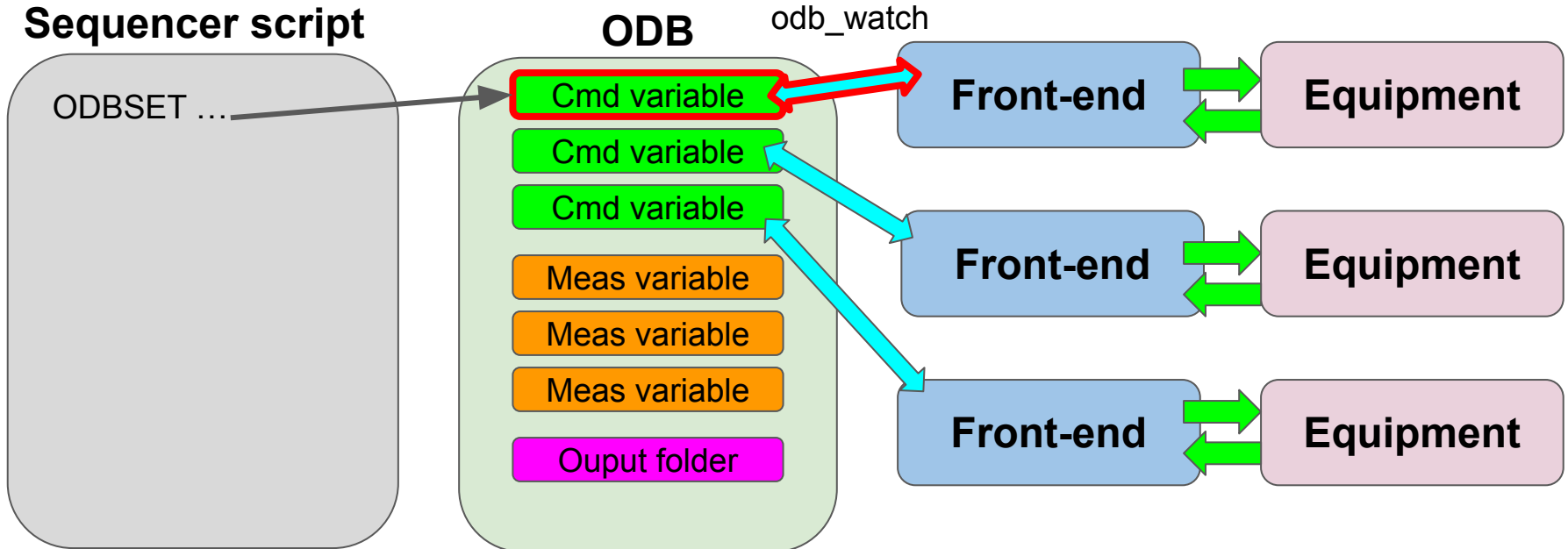




# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script

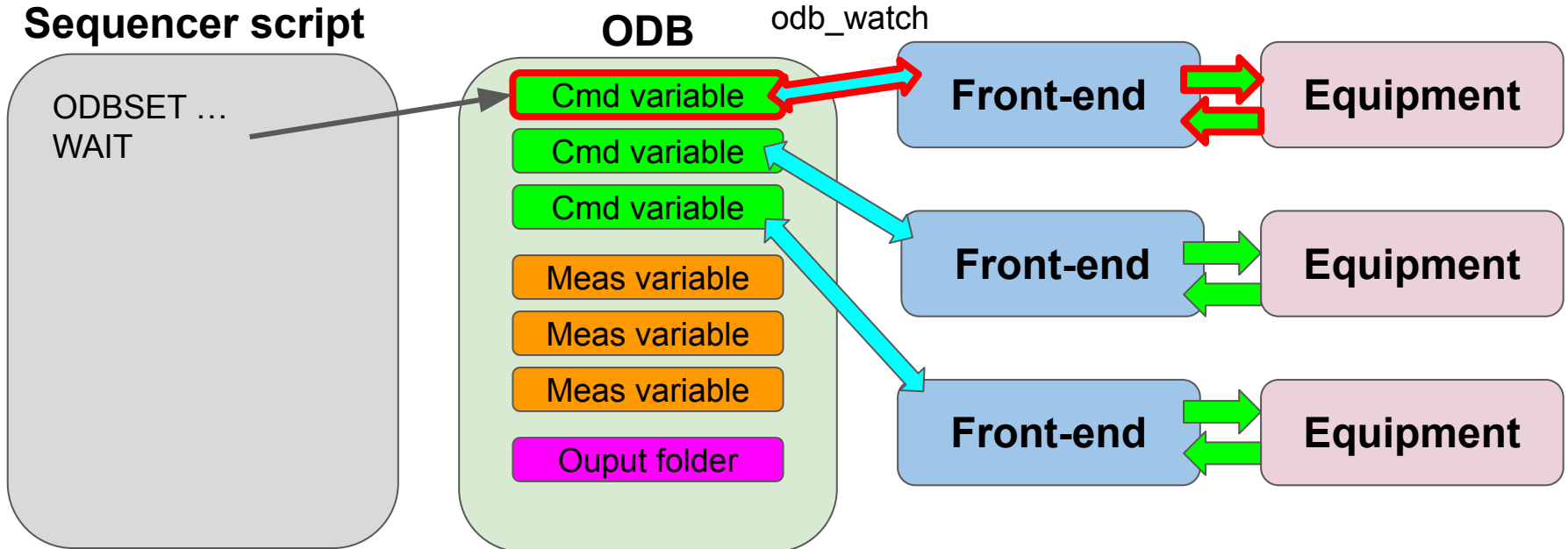




# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script

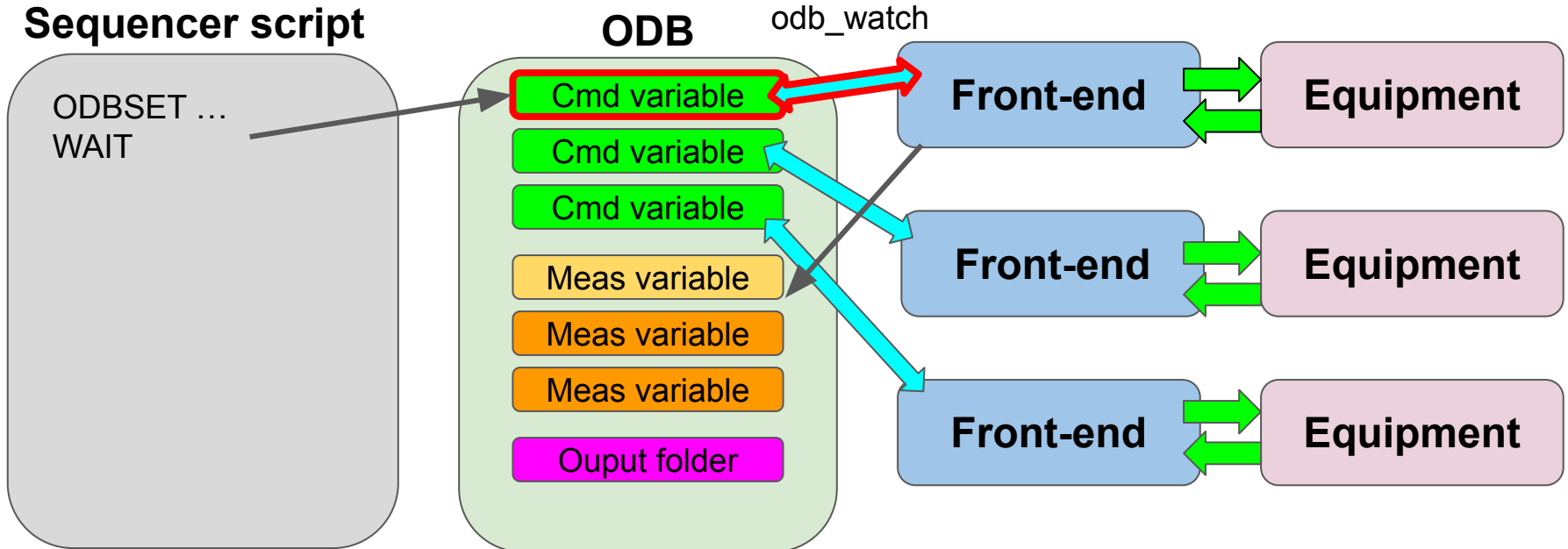




# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script

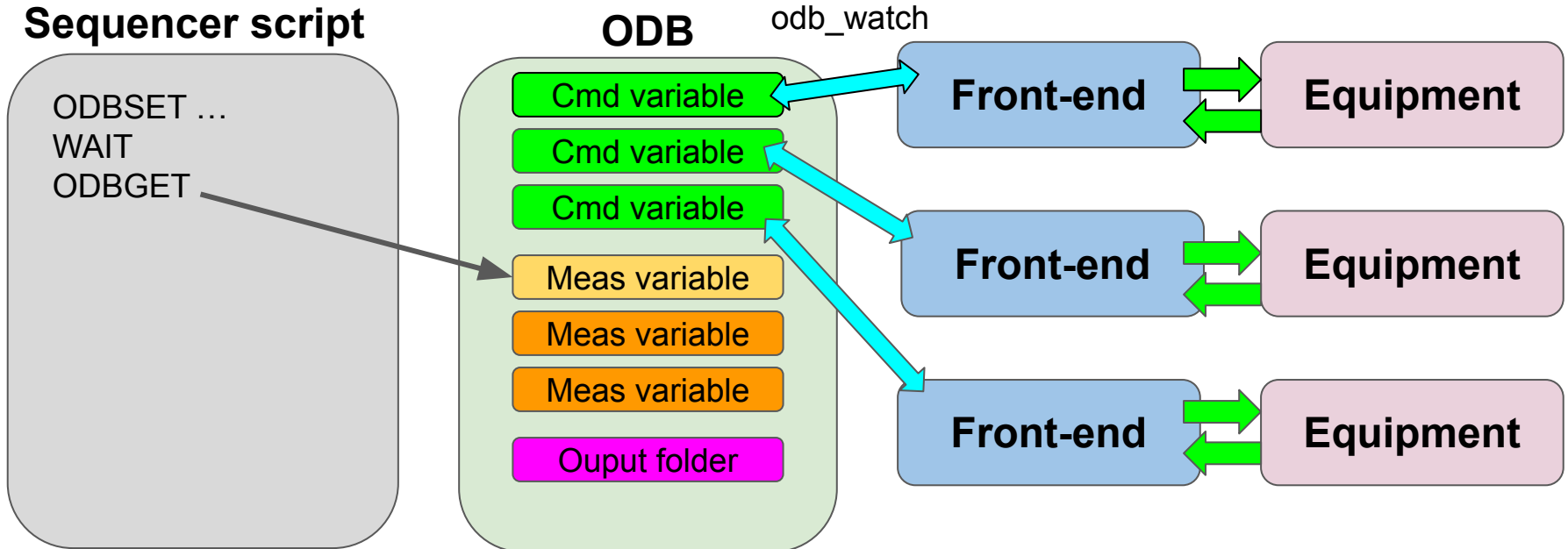




# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script

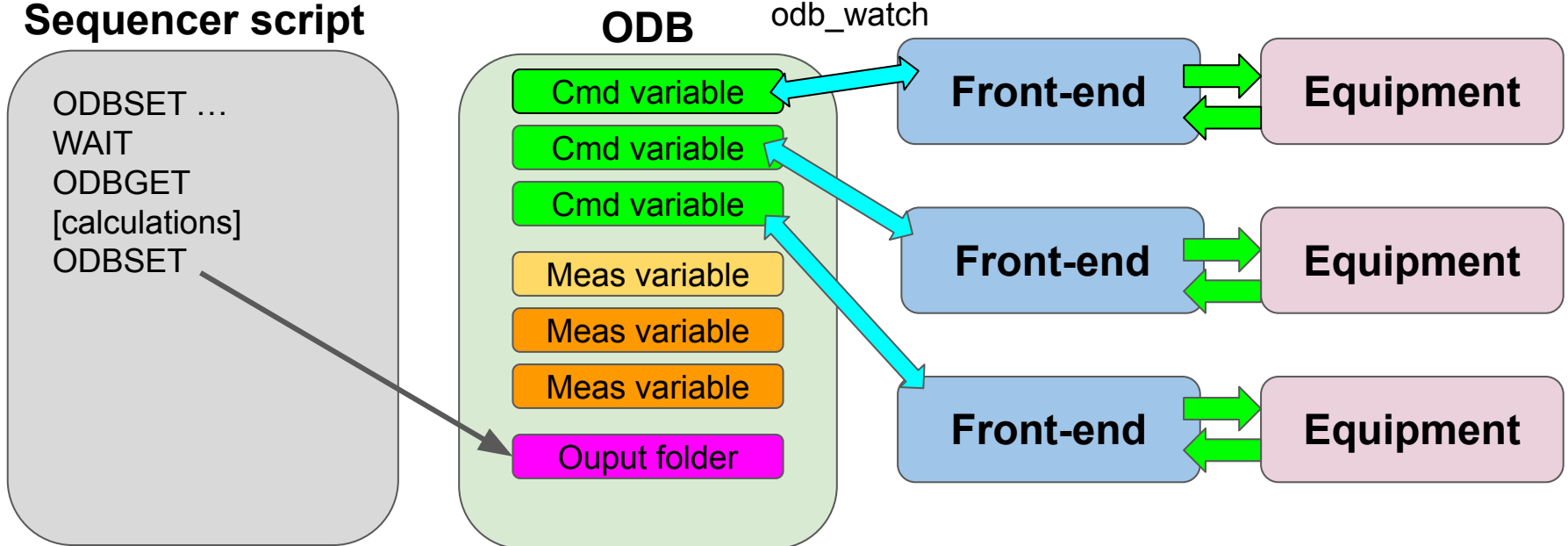




# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script





# QC test setup: software principle

One full QC test is a sequence of single tests

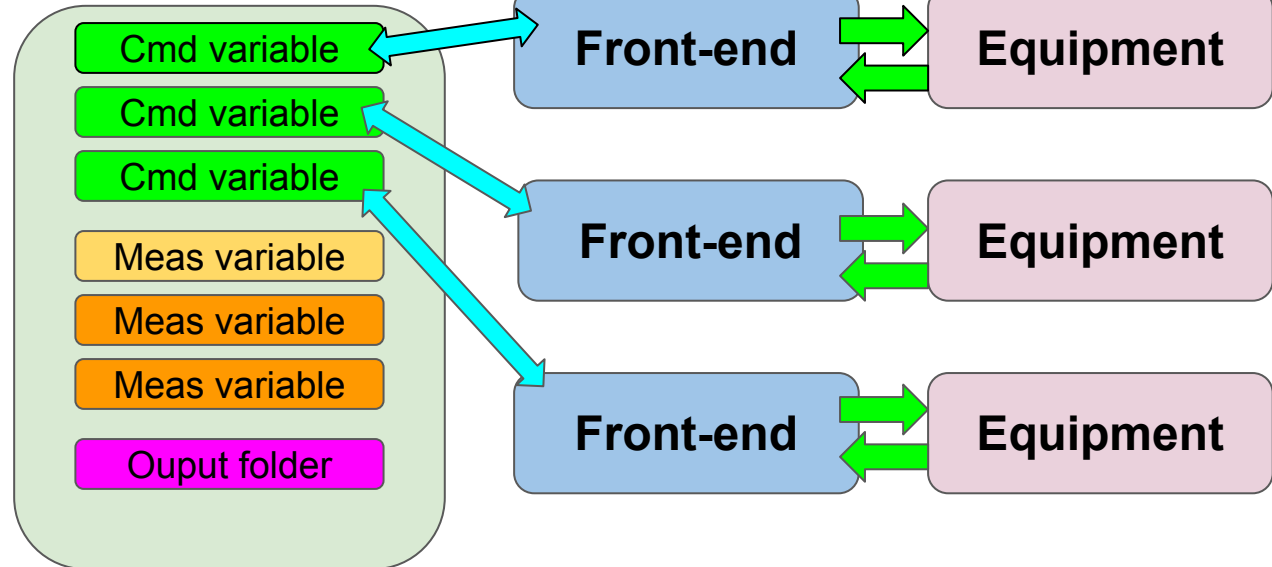
Each single test is run by a sequencer script

## Sequencer script

```
ODBSET ...  
WAIT  
ODBGET  
[calculations]  
ODBSET  
[repeat in loops]
```

## ODB

odb\_watch





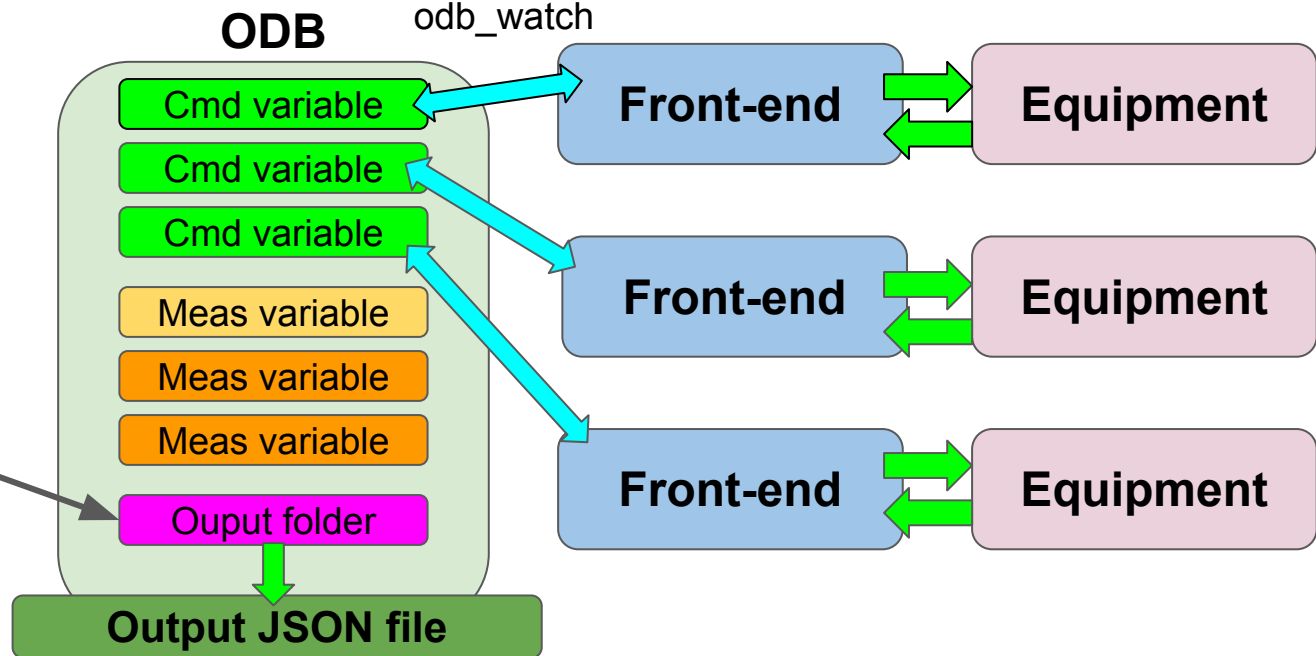
# QC test setup: software principle

One full QC test is a sequence of single tests

Each single test is run by a sequencer script

## Sequencer script

```
ODBSET ...  
WAIT  
ODBGET  
[calculations]  
ODBSET  
[repeat in loops]  
ODBSAVE
```





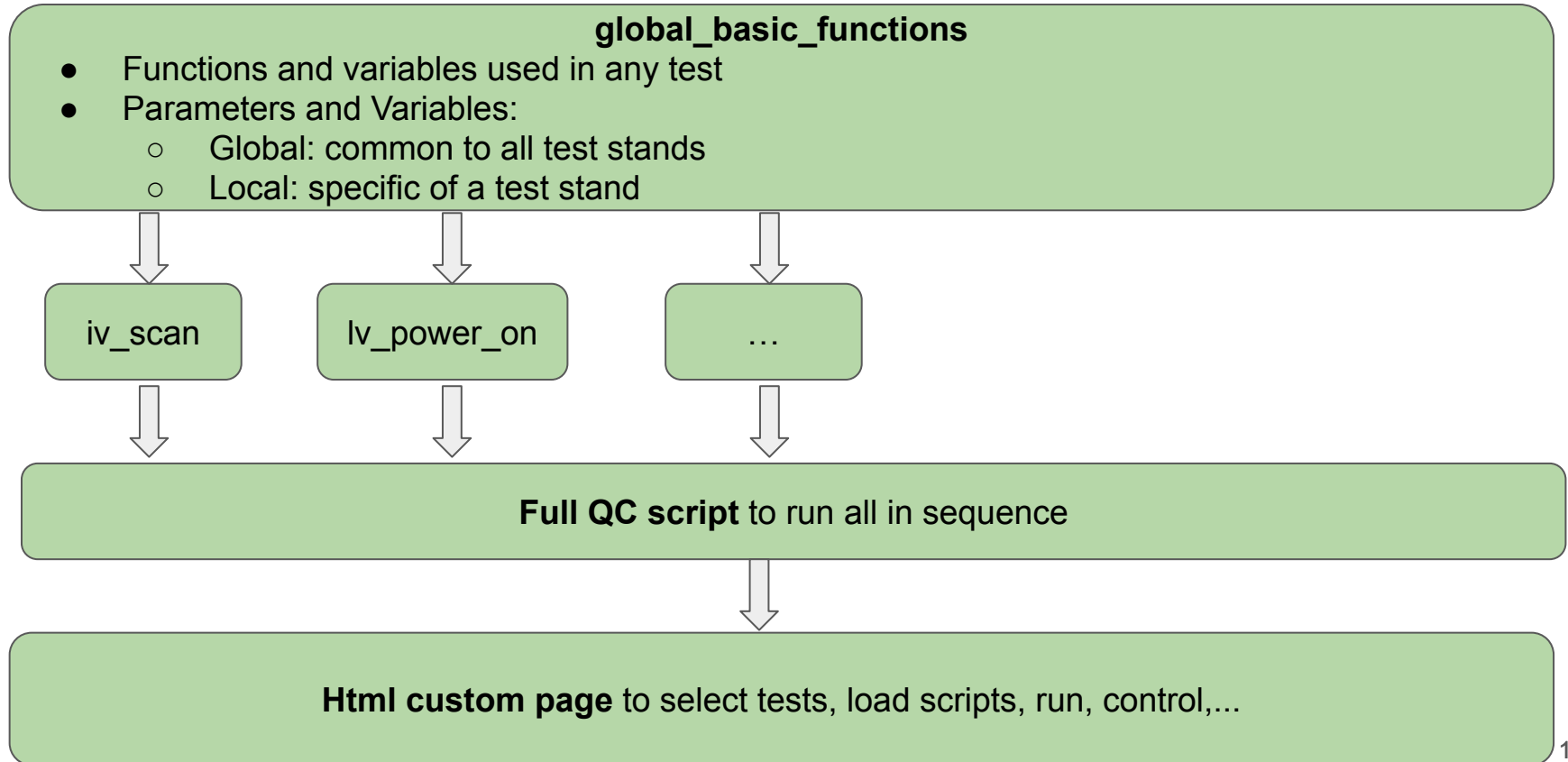
# Special case: analyzer

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- What reported so far works nicely for “slow control”
  - With pixel data (64,000 pixels per chip) not possible to work with ODB calls
- The Mu3e DAQ takes data from the chip and dump them to Midas events
- An analyzer based on manalyzer runs in parallel with the QC
  - The analyzer can interact with the ODB via odbxx
- The procedure is then
  - Sequencer script starts run and wait the necessary time
  - Analyzer collects and analyze data (AnalyzeFlowEvent)
  - Sequencer script stops run
  - Analyzer extracts the relevant measurements from the data (end of run function)
  - Analyzer writes the relevant measurements in the ODB
  - Sequencer scripts gets those measurements for its algorithm
- **Analyzer acts like a front-end**

# QC test: file structure



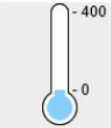
# QC test: custom page



## Control parameters

Sequencer status	
Name	Value
Sequencer running	<input checked="" type="checkbox"/>
Sequencer file	configure_chip.msl

ADC Readings	
Name	Value
BL	0.0012689328
BLPix	0.001308514
TemperatureDiode	2.7086816
TestOut	0.0013162207
ThPix	-0.00017555431
ThHigh	-0.000084959902
ThLow	-0.000060803723

Monitoring	
LV current	<input checked="" type="checkbox"/> On
HV current	<input checked="" type="checkbox"/> On
Heat dissipation:	 0.00 mW/cm <sup>2</sup>

General Chip Configuration	
Name	Value
Is Mupix11	<input checked="" type="checkbox"/>
Use Serial Input	<input checked="" type="checkbox"/>
Chip Type	0x017e

Links					
	Link	Locked	Ready	Disperr	Num Hits
A	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	125473379	0
B	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	125473377	0
C	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	125473381	0
D	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	125473378	0

## Power Setup    Manual Chip Control    QC tests

HV SUPPLY (192.168.0.068)						
Channel	State	Demand	Voltage	Current	Limit	Current (uA) Description
0	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	-5	5.000e+0	2.000e-5	1.694e-5 HV SUPPLY

LV SUPPLY						
Channel	State	Demand	Voltage	Current	Limit	Current Description
0	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	2.07	2.07	1.000	0.000 Chip Power
1	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	24.00	24.00	1.000	0.180 SCS/3000
2	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	17.00	17.00	1.000	0.674 FEB
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	2.00	0.00	1.000	0.000 Fan

# QC test: custom page



Power Setup Manual Chip Control **QC tests**

Object ID  
Part No. Lot No. Item No.  
382 3 31

Start Chip QC

Choose a QC test:  
Full

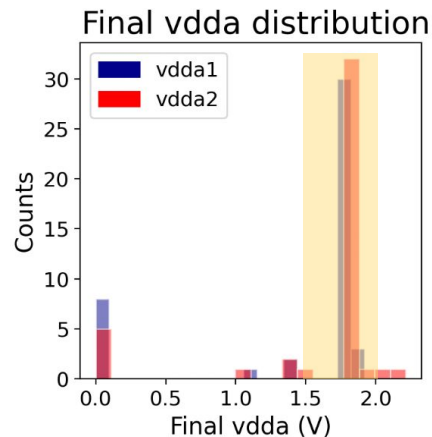
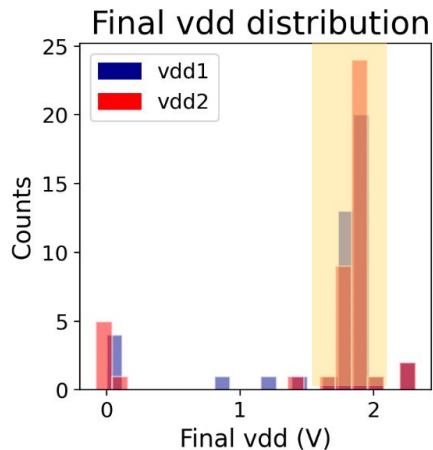
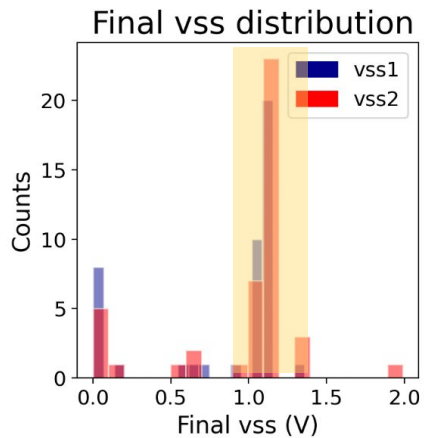
Parameters	
Name	Value
Low voltage (V)	\$global_lv_voltage
HV voltage (V)	\$global_hv_voltage
HV current limit (uA)	\$global_hv_current_limit
IV scan LV off (boolean)	1
IV scan LV on (boolean)	0
IV scan chip configured (boolean)	1
IV scan: HV start voltage (V)	0
IV scan: HV stop voltage (V)	27
IV scan: HV step size (V)	2
IV scan: HV fine step size (V)	0.5
IV scan: Current fraction (fine steps)	0.5
Power on: HV on (boolean)	1
on-chip Volt: Adjust voltage (boolean)	1
on-chip Volt: Number of iterations	2
on-chip Volt: VDD(A) target voltage	\$global_vdd_target_voltage
on-chip Volt: VSSA target voltage	\$global_vss_target_voltage
VDAC scan: THHigh start	90
VDAC scan: THHigh stop	120
VDAC scan: THHigh steps	5
VDAC scan: THLow start	90
VDAC scan: THLow stop	120
VDAC scan: THLow steps	5
VDAC scan: Baseline start	85
VDAC scan: Baseline stop	115
VDAC scan: Baseline steps	5
VDAC scan: BLPix start	60
VDAC scan: BLPix stop	160
VDAC scan: BLPix steps	10
VDAC scan: ref_Vss start	140
VDAC scan: ref_Vss stop	210
VDAC scan: ref_Vss steps	10
VDAC scan: Sequential scan (boolean)	0
LVDS links: VPVCO start	12
LVDS links: VPVCO stop	37
LVDS links: VNVCO start	\$VPVCO_start+1
LVDS links: VNVCO stop	\$VPVCO_stop+1
LVDS links: VCO step size	5

QC grading parameters:	
Name	Value
Max. allowed QC score	10
no FullQC canceling (boolean)	1
FAIL Minimum HV	10
GRADE Operational HV	25
FAIL Min. LV current (mA) Bias Off	20.0
FAIL Min. LV current (mA) Bias On	300.0
FAIL Max. LV current (mA) Bias Off	200.0
FAIL Max. LV current (mA) Bias On	600.0
GRADE Min. LV current (mA) Bias Off	30.0
GRADE Min. LV current (mA) Bias On	400.0
GRADE Max. LV current (mA) Bias Off	100.0
GRADE Max. LV current (mA) Bias On	500.0
FAIL Min. TempDiode Voltage	0.5
FAIL Max. TempDiode Voltage	1.1
FAIL Max. ΔVDD to target voltage	0.1
FAIL Max. ΔVSSA to target voltage	0.1
GRADE Max. ΔVDD to target voltage	0.025
GRADE Max. ΔVSSA to target voltage	0.025
GRADE Max. AVG VDD(A) deviations	0.05
GRADE Max. AVG VSSA deviations	0.05
TARGET THHigh Slope (V/DAC)	0.0065
FAIL THHigh slope difference (rel.)	0.2
GRADE THHigh slope difference (rel.)	0.1
FAIL THHigh AVG rel. slope deviations	0.001
GRADE THHigh AVG rel. slope deviations	0.005
TARGET THLow Slope (V/DAC)	0.0
FAIL THLow slope difference (rel.)	0.2
GRADE THLow slope difference (rel.)	0.1
FAIL THLow AVG rel. slope deviations	0.001
GRADE THLow AVG rel. slope deviations	0.0005
TARGET Baseline Slope (V/DAC)	0.0065
FAIL Baseline slope difference (rel.)	0.2
GRADE Baseline slope difference (rel.)	0.1
FAIL Baseline AVG rel. slope deviations	0.001
GRADE Baseline AVG rel. slope deviations	0.0005
TARGET BLPix Slope (V/DAC)	0.0065
FAIL BLPix slope difference (rel.)	0.2
GRADE BLPix slope difference (rel.)	0.1
FAIL BLPix AVG rel. slope deviations	0.001
GRADE BLPix AVG rel. slope deviations	0.0005
TARGET ref_Vss Slope (V/DAC)	0.006
FAIL ref_Vss slope difference (rel.)	0.5
GRADE ref_Vss slope difference (rel.)	0.1
FAIL ref_Vss AVG rel. slope deviations	0.002
GRADE ref_Vss AVG rel. slope deviations	0.0005

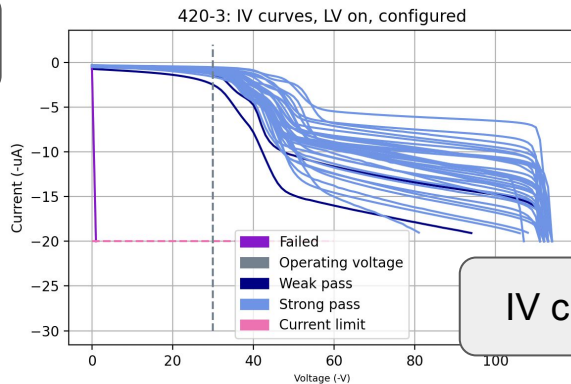
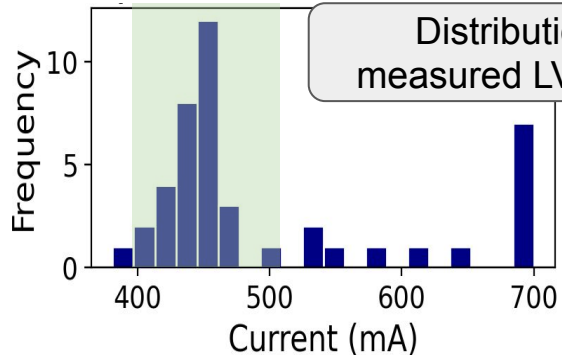
The html page takes care of the interaction with the sequencer (load script, set parameters, start)

Generally the default parameters work, only experts will change them

# QC test: sparse results



Distributions of measured voltages



IV curves

A.L. Fuchs

# QC setup: near future improvements

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These scripts will become the basis of all QC tests for Mu3e Pixels

More elaborate components will be tested, with up to 36 chips at the same time

Efforts are being made to have more flexible testing schemes:

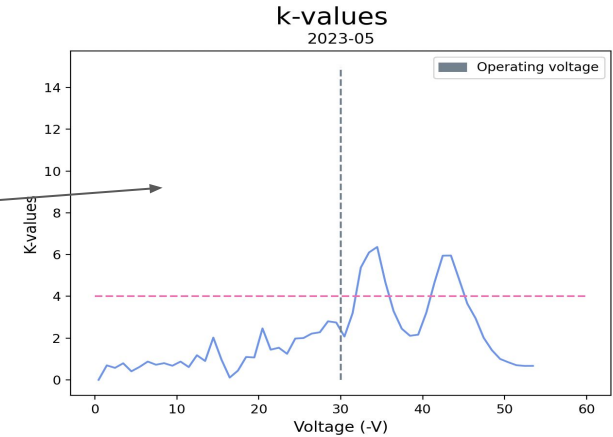
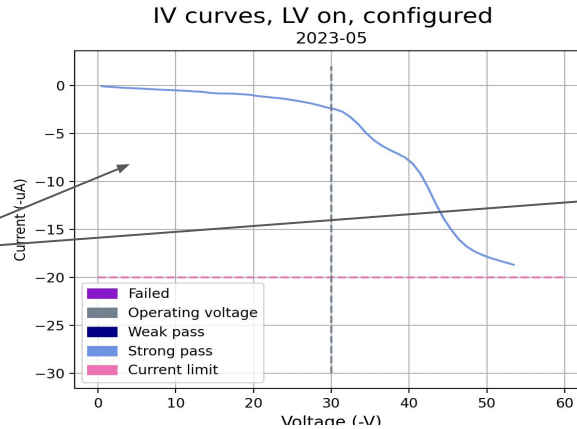
- More elaborate ODB folders for configuration and output
  - to loop over all chips in the system
- More dynamic html custom page

# QC setup: further future improvements



## Online Plots!

Examples from the analysis code



It would be nice to have them running online

The x and y axes are vectors in the ODB

Javascript library coming...?

Not really necessary in the long run (ideally once the QC works no need to check the page)

# QC setup: even further future improvements

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## Integrate Python API...?

- Analysis code written in Python
  - More elaborate calculations (cross-test correlations, multiple chips,...)
  - It loads the output JSON files
- The analysis could work online alongside the testing procedure
  - It will access directly the values in the ODB
  - Updating results as it goes



# Why sequencer?

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Possible other candidates would be Javascript pages, Python API, or special frontend,...

- Test routines use sequential commands
  - Javascript async
- Test routines can be executed remotely and possibly by more people
  - Everybody can see if the sequencer is running
  - Less risk of conflict

**The QC scripts will be the blueprint for calibration procedures in the experiment!**



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# Backup

# QC test setup: relevant details

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Some features implemented in Midas to perform Mu3e pixel QC test

- ODBSAVE command to save an ODB folder in JSON format
- TinyExpr library to convert more complicated math expressions

Small gimmicks:

- Generic functions to be used by all scripts are defined in the entry script as SUBROUTINES
  - They can not have return statements
  - All return variables defined in entry script and changed by the subroutines
- We want to run all tests in sequence or just one at a time
  - For each test 2 scripts:
    - The first contains the routine itself as one subroutine
    - The latter sets the input parameters and run the subroutine from the first
  - The full QC script loads all the scripts containing the routines and sets all parameters